Effects of Nanostructure Geometry on Nanoimprinted Polymer Photovoltaics

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Supporting Information

Fig. S1 Schematic of GIXRD setups for (a) out-of-plane measurement with scan axis of 2θ and (b) in-plane measurement with scan axis of φ/2θX. The incident X-rays in both setups are at a small incident angle ω to the plane of sample surfaces.